Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination
10/072,212	NAYAK ET AL.
Examiner	Art Unit
Kou-Yi K. Chen	2193

	SEAR	CHED	
Class	Subclass	Date	Examiner
717	114, 136- 140	3/29/2006	K.C.
716	1-18	3/29/2006	K.C.
703	13-28	3/29/2006	K.C.

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB (limited classified search)	3/29/2006	K.C.
Inventor name search	3/29/2006	K.C.
Google/IEEE/ACM search	3/29/2006	K.C.
Consulted SPE with 101/112 issue	3/31/2006	K.C.